## Notice of References Cited Application/Control No. 10/537,690 Examiner DEAN KWAK Applicant(s)/Patent Under Reexamination STRAND ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,580,523 A	12-1996	Bard, Allen J.	422/50
*	В	US-6,306,659 B1	10-2001	Parce et al.	436/47
*	C	US-6,386,219 B1	05-2002	Barth et al.	137/15.01
*	D	US-6,443,179 B1	09-2002	Benavides et al.	137/454.2
*	Е	US-6,494,614 B1	12-2002	Bennett et al.	366/336
*	F	US-2003/0012697 A1	01-2003	Hahn et al.	422/99
*	G	US-6,525,343 B1	02-2003	Tanga, Michifumi	257/77
*	Ι	US-6,790,526 B2	09-2004	Vargo et al.	428/343
	-	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.